



Superior Magnetics Since 1979

CMOQ-1

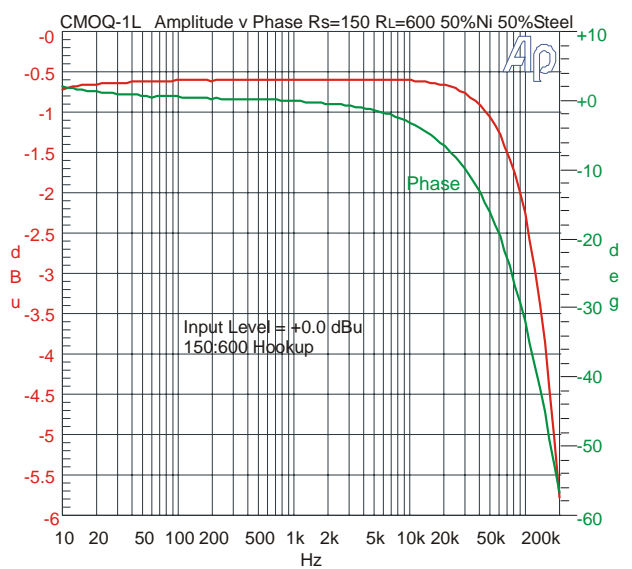
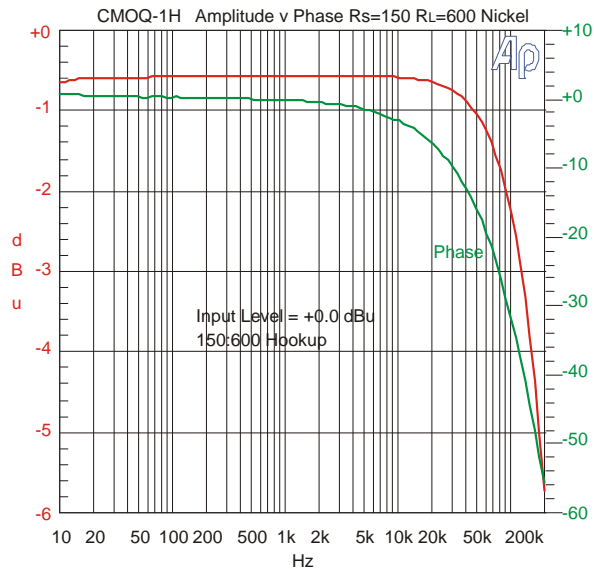
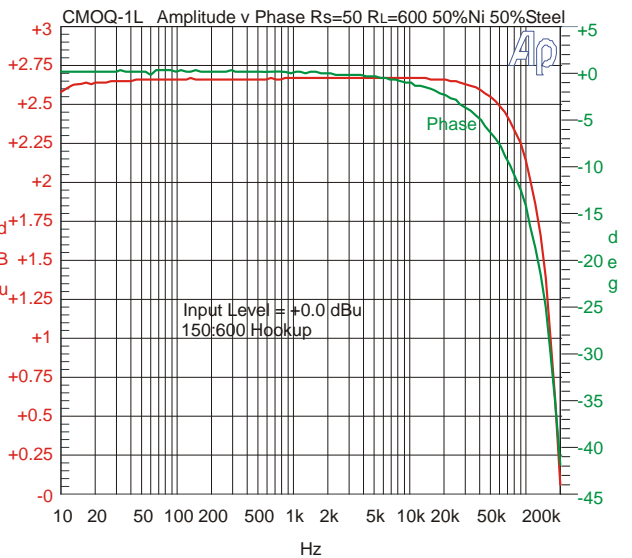
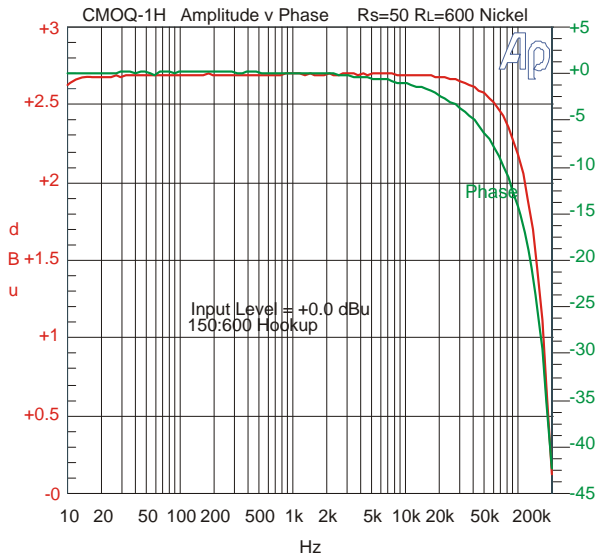
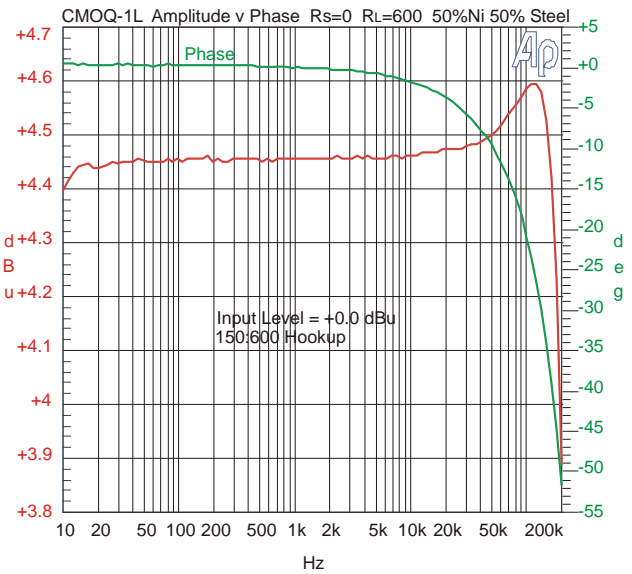
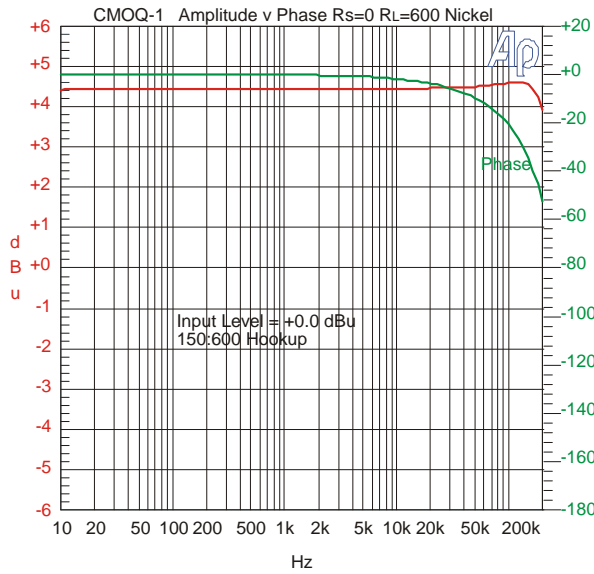
LINE OUTPUT TRANSFORMER
Quadfilar Windings

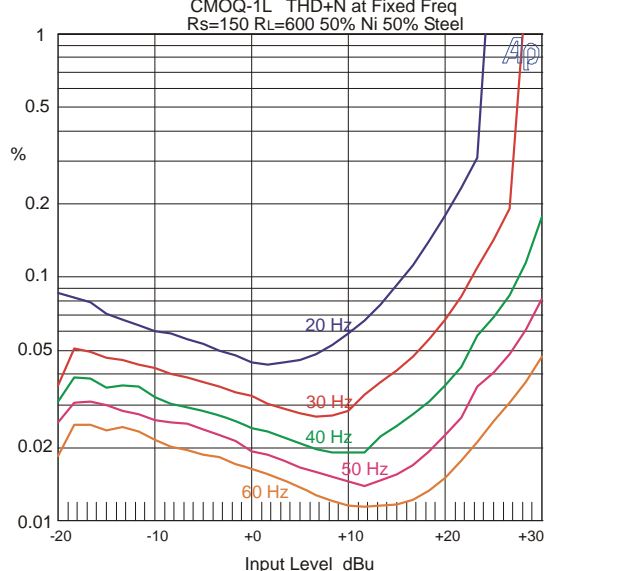
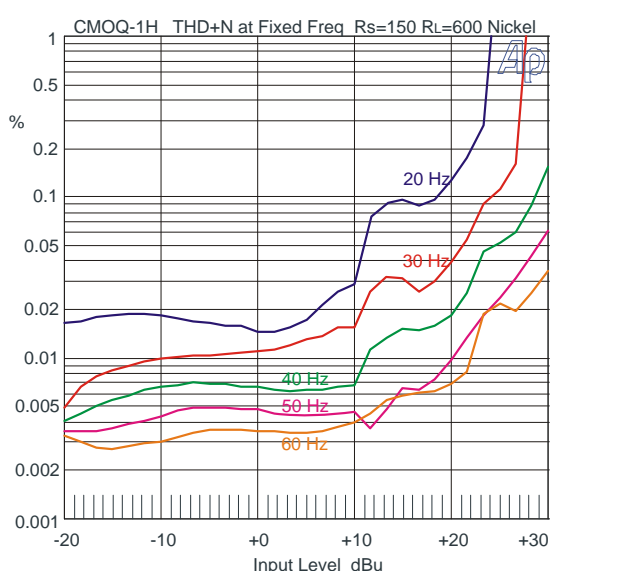
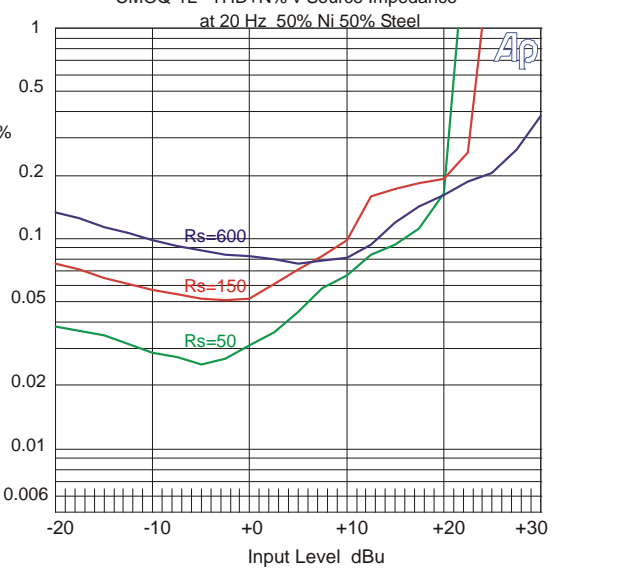
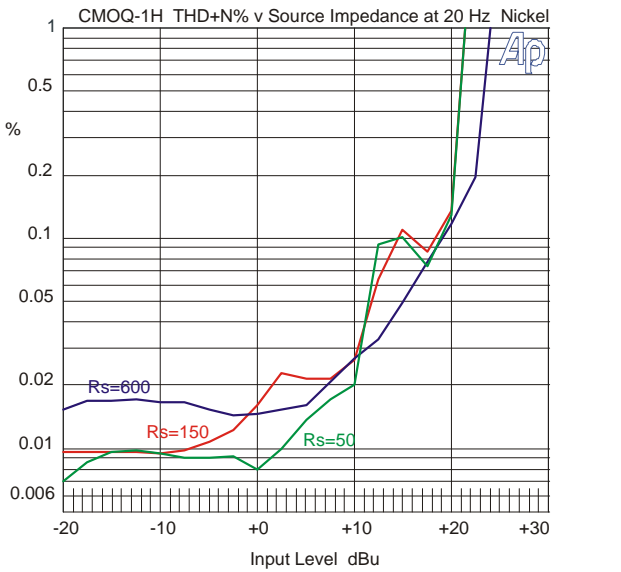
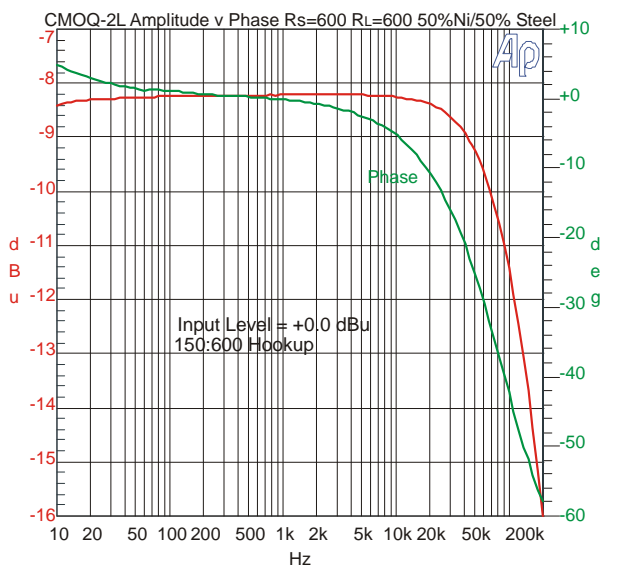
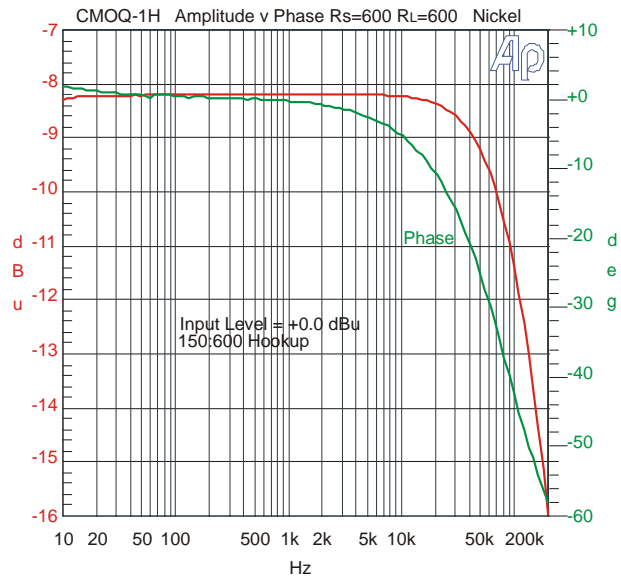
- **Excellent bandwidth: -3 dB at 150 kHz**
- **{Rs=150S 80% Nickel (“HiNi”) laminations}**
- **Distortion 0.02% typ at 20 Hz, Rs=150S HiNi**
- **+24 dBm at 20 Hz, 1% THD+N Rs≤150S**
- **Phase Shift -6E at 20 kHz, Rs=150S**
- **Low insertion loss**

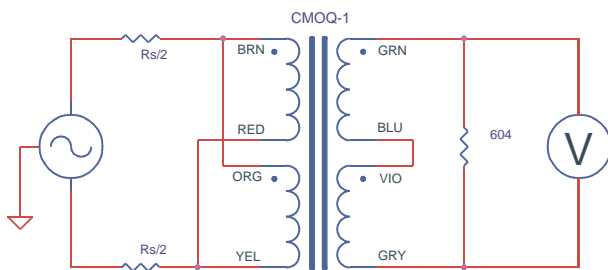
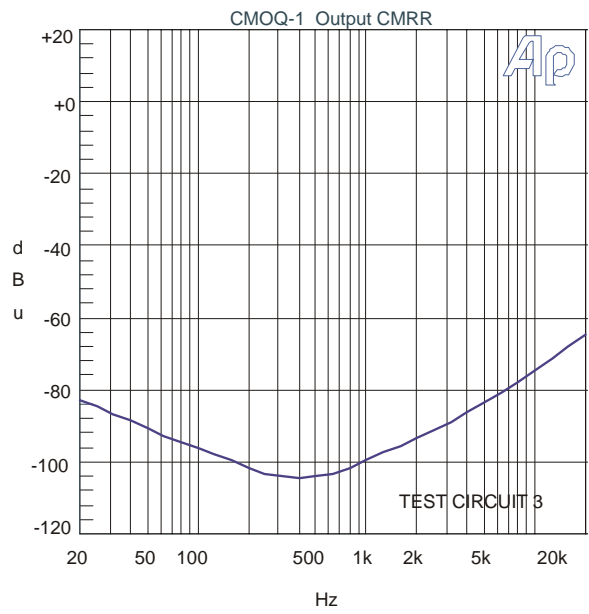
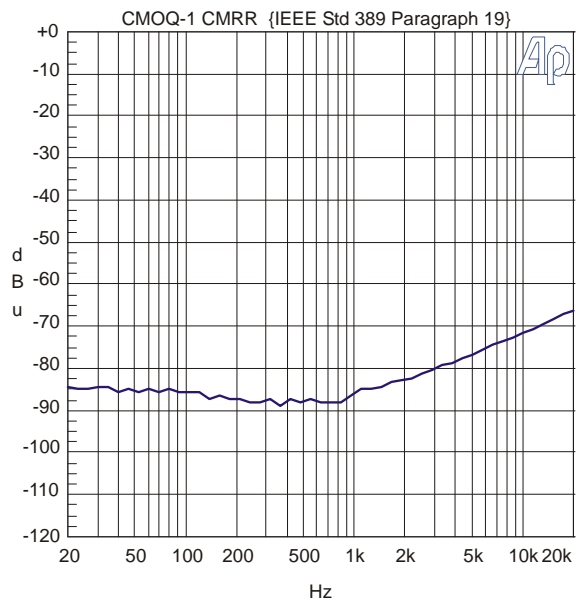
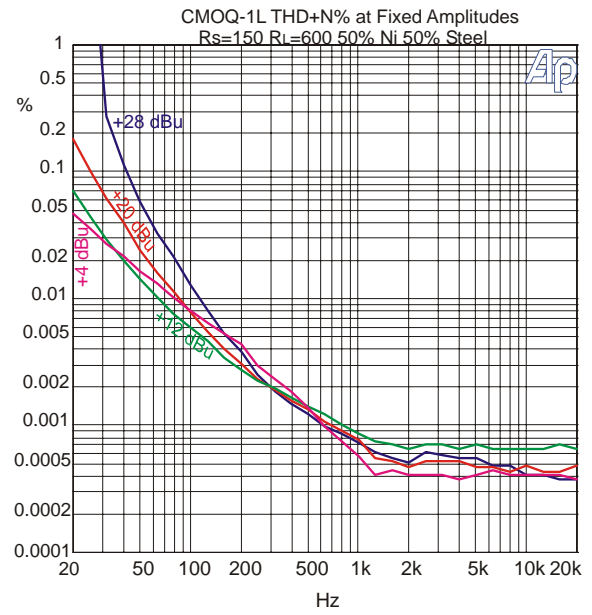
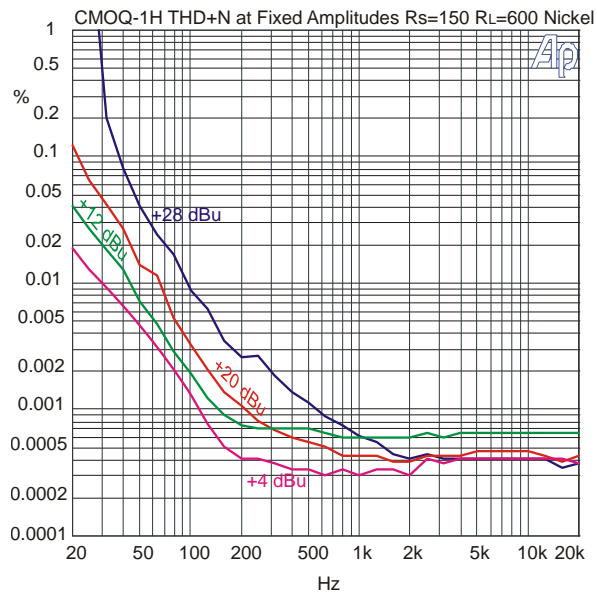
The CineMag CMOQ-1 output transformer uses quadfilar construction techniques. This four-winding transformer delivers good coupling between windings as well as excellent bandwidth. It is available both with 80% Nickel (“HiNi”) and 50% Nickel/50% Steel laminations. It can be driven with source impedances of up to 600S. As with all line driving devices, the amplifier feeding it must be capable of cleanly delivering the power required to reach maximum operating level. See AN-102.

CMOQ-1H / CMOQ-1L

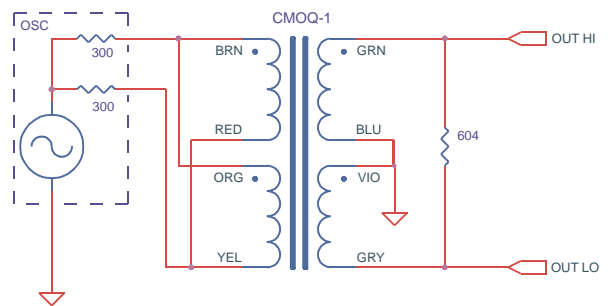
Parameter	Conditions	Typ
Turns Ratio		1 : 1.00
Input Impedance, Zi	20 Hz to 20 kHz, +0 dBu Test Circuit 4	620S
Voltage Gain	1 kHz HiNi Core, 150S :600S Rs=0 1 kHz 50% Nickel/50% Steel Core, Rs=0	+4.45 dB +4.45 dB
Distortion (THD+N%)	1 kHz, +4 dBu, Rs=150 HiNi Test Circuit 1 1 kHz, +4 dBu, Rs=150 50%Ni/50% Steel	0.0003% 0.0006%
Max 20 Hz input level	1.0% THD+N, Rs≤150 HiNi Test Circuit 1 1.0% THD+N, Rs≤150 50% Ni 50% Steel	+24 dB +24 dB
Response, ref 1 kHz	20 Hz Rs=150S HiNi Test Circuit 1 20 kHz Rs=150S HiNi Test Circuit 1 -3dBu Rs=150S HiNi Test Circuit 1	-0.01 dB -0.01 dB 150 kHz
Phase Shift at 20Hz Phase Shift at 20 kHz	Referenced to source generator Test Circuit 1	+0.1E -6E
CMRR	60 Hz Test Circuit 2 per IEEE Std 389-1996 ¶19 1 kHz Test Circuit 2 per IEEE Std 389-1996 ¶19	85 dB 84dB
Output CMRR	60 Hz Test Circuit 3 1 kHz Test Circuit 3	85 dB 85 dB
Operating Temp Range	Operation and storage	0E C Min 70E C Max



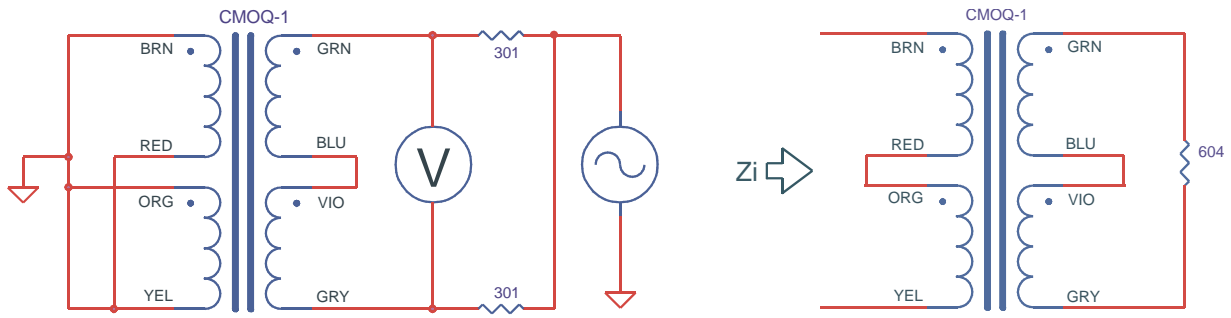




TEST CIRCUIT 1



TEST CIRCUIT 2



TEST CIRCUIT 3

TEST CIRCUIT 4

NOTES:

1. All graphs generated from one (1) randomly chosen device. No statistical averaging or weighting. Data from one sweep.
2. $R_L = 604$ unless otherwise noted.

